



Title: IMPROVING SEM INSPECTION AND ANALYSIS OF PATTERNED PHOTORESIST FEATURES

Inventor(s): Uzodinma Okoroanyanwu et al.

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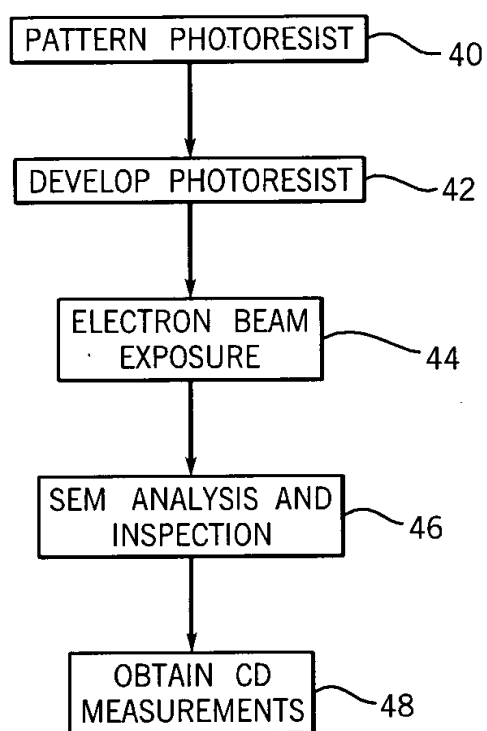


FIG. 1

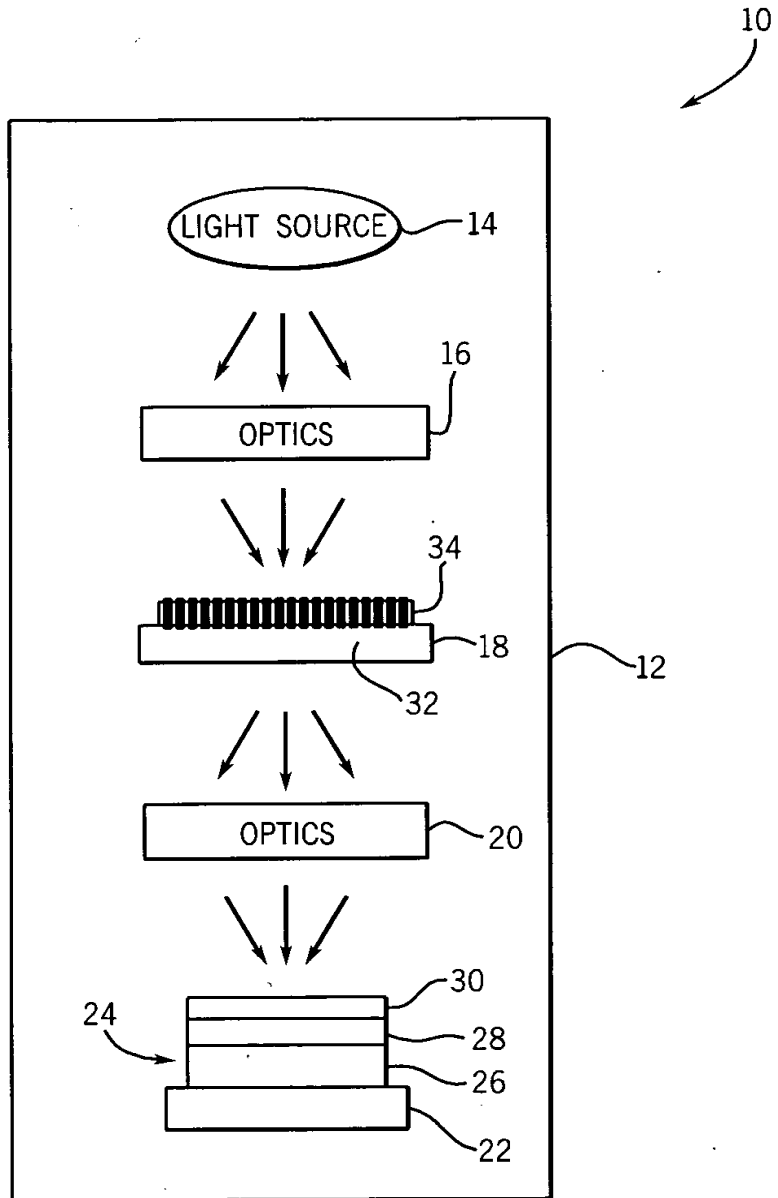


FIG. 2



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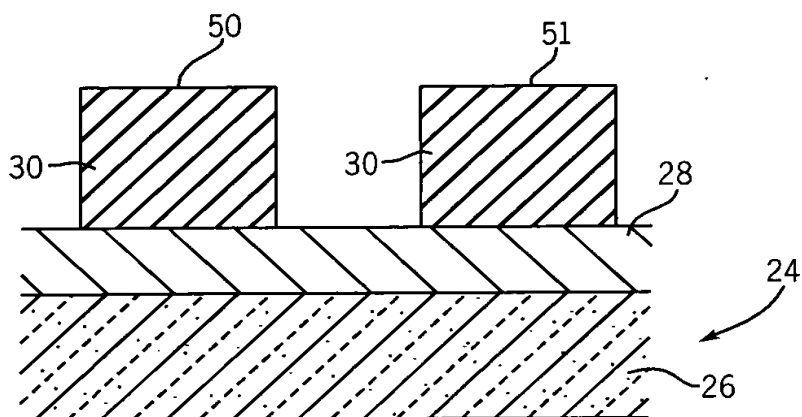


FIG. 3

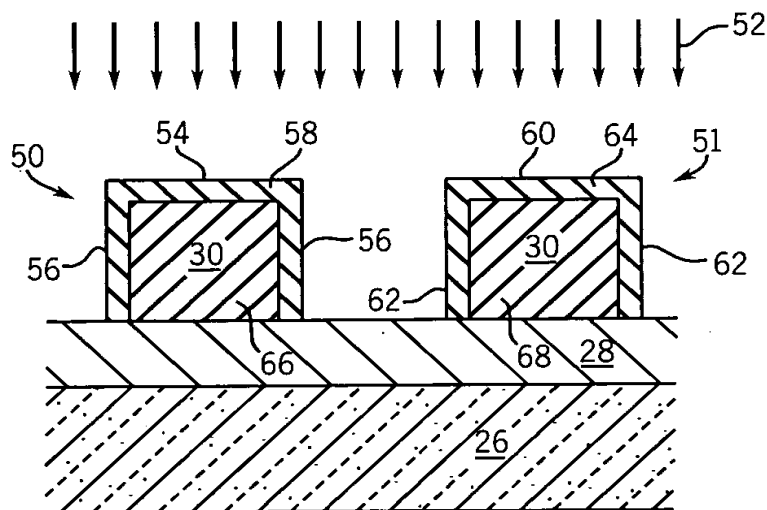


FIG. 4

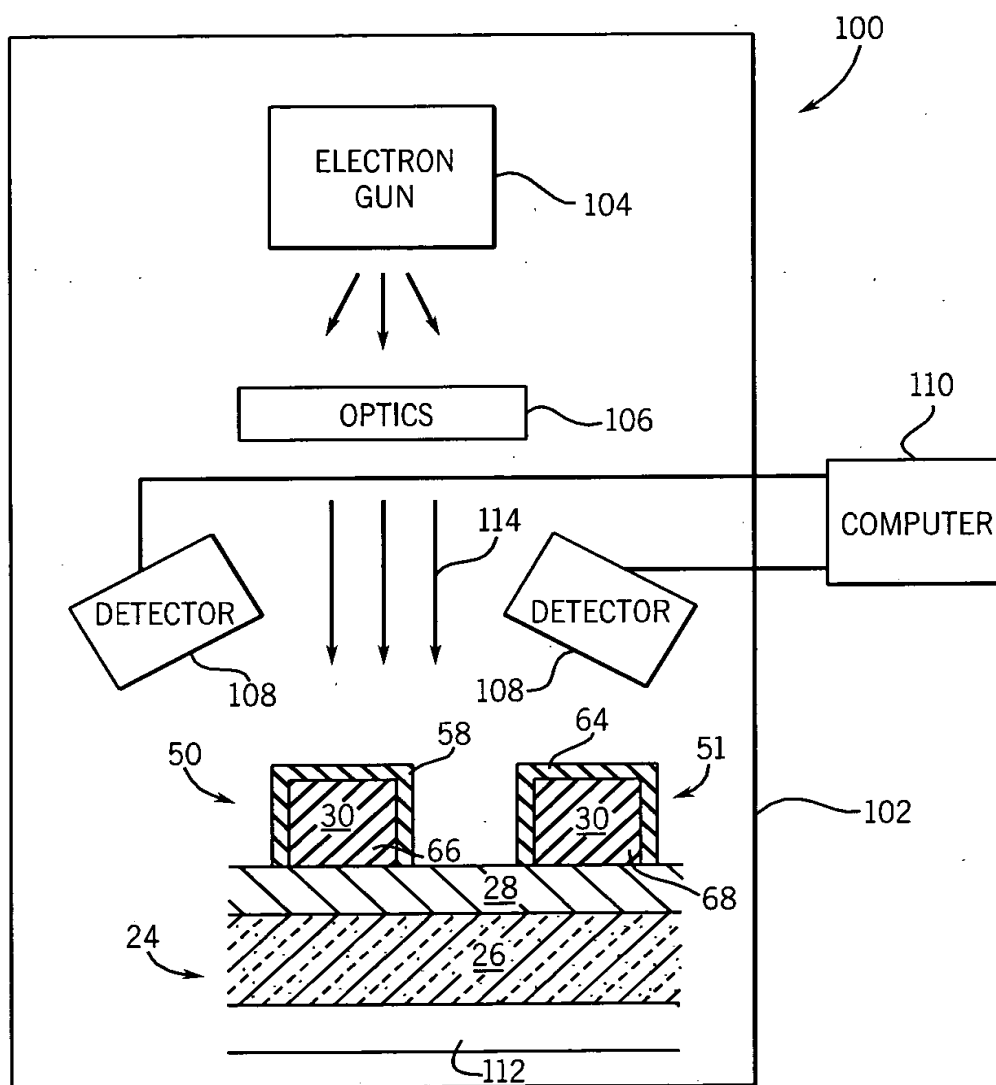


FIG. 5